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SCLS467E - FEBRUARY 2003-REVISED DECEMBER 2012

DUAL RETRIGGERABLE MONOSTABLE MULTIVIBRATOR WITH SCHMITT-TRIGGER INPUTS

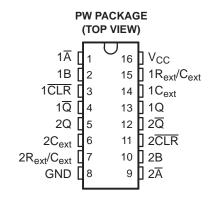
Check for Samples: SN74LV123A-Q1

FEATURES

- Qualified for Automotive Applications
- Typical V_{OLP} (Output Ground Bounce)
 <0.8 V at V_{CC} = 3.3 V, T_A = 25°C
- Typical V_{OHV} (Output V_{OH} Undershoot)
 >2.3 V at V_{CC} = 3.3 V, T_A = 25°C
- Supports Mixed-Mode Voltage Operation on All Ports
- Schmitt-Trigger Circuitry on A, B, and CLR Inputs for Slow Input Transition Rates
- Edge Triggered From Active-High or Active-Low Gated Logic Inputs
- I_{off} Supports Partial-Power-Down Mode Operation
- Retriggerable for Very Long Output Pulses, up to 100% Duty Cycle
- Overriding Clear Terminates Output Pulse
- Glitch-Free Power-Up Reset on Outputs

ESD Protection Exceeds JESD 22

- 2000-V Human-Body Model (A114-A)
- 200-V Machine Model (A115-A)
- 1000-V Charged-Device Model (C101)



DESCRIPTION/ORDERING INFORMATION

The SN74LV123A is a dual retriggerable monostable multivibrator designed for 2-V to 5.5-V V_{CC} operation.

This edge-triggered multivibrator features output pulse-duration control by three methods. In the first method, the \overline{A} input is low, and the \overline{A} input goes high. In the second method, the \overline{B} input is high, and the \overline{A} input goes low. In the third method, the \overline{A} input is low, the \overline{B} input is high, and the clear (\overline{CLR}) input goes high.

The output pulse duration is programmable by selecting external resistance and capacitance values. The external timing capacitor must be connected between C_{ext} and $R_{\text{ext}}/C_{\text{ext}}$ (positive) and an external resistor connected between $R_{\text{ext}}/C_{\text{ext}}$ and V_{CC} . To obtain variable pulse durations, connect an external variable resistance between $R_{\text{ext}}/C_{\text{ext}}$ and V_{CC} . The output pulse duration also can be reduced by taking $\overline{\text{CLR}}$ low.

Pulse triggering occurs at a particular voltage level and is not directly related to the transition time of the input pulse. The A, B, and CLR inputs have Schmitt triggers with sufficient hysteresis to handle slow input transition rates with jitter-free triggering at the outputs.

Once triggered, the basic pulse duration can be extended by retriggering the gated low-level-active (\overline{A}) or high-level-active (B) input. Pulse duration can be reduced by taking CLR low. The input/output timing diagram illustrates pulse control by retriggering the inputs and early clearing.

During power up, Q outputs are in the low state, and \overline{Q} outputs are in the high state. The outputs are glitch free, without applying a reset pulse.

This device is fully specified for partial-power-down applications using I_{off} . The I_{off} circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



ORDERING INFORMATION(1)

T _A	PAC	(AGE ⁽²⁾	ORDERABLE PART NUMBER	TOP-SIDE MARKING
-40°C to 105°C	TSSOP - PW	Tape and reel	SN74LV123ATPWRQ1	LV123AQ

- (1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at www.ti.com.
- (2) Package drawings, thermal data, and symbolization are available at www.ti.com/packaging.

Table 1. FUNCTION TABLE (EACH MULTIVIBRATOR)

	INPUTS		OUTPUTS			
CLR	Ā	В	Q	Q		
L	Χ	Χ	L	Н		
X	Н	X	L ⁽¹⁾	H ⁽¹⁾		
X	X	L	L ⁽¹⁾	H ⁽¹⁾		
Н	L	↑	Л	Т		
Н	\downarrow	Н	Л	Т		
↑	L	Н	Л	T		

(1) These outputs are based on the assumption that the indicated steady-state conditions at the A and B inputs have been set up long enough to complete any pulse started before the setup.

Figure 1.
LOGIC DIAGRAM, EACH MULTIVIBRATOR (POSITIVE LOGIC)

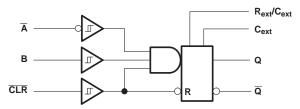
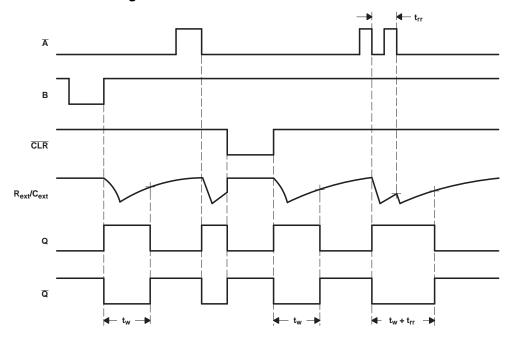


Figure 2. INPUT/OUTPUT TIMING DIAGRAM



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Absolute Maximum Ratings(1)

over operating free-air temperature (unless otherwise noted)

			MIN	MAX	UNIT
V_{CC}	Supply voltage range		-0.5	7	V
V_{I}	Input voltage range ⁽²⁾		-0.5	7	V
Vo	Voltage range applied to any output in t	the high-impedance or power-off state ⁽²⁾	-0.5	7	V
Vo	Output voltage range in the high or low	state (2) (3)	-0.5	V _{CC} + 0.5	V
Vo	Output voltage range in power-off state	(2)	-0.5	7	٧
I_{IK}	Input clamp current	V _I < 0		-20	mA
I _{OK}	Output clamp current	V _O < 0		-50	mA
Io	Continuous output current	$V_O = 0$ to V_{CC}		±25	mA
	Continuous current through V _{CC} or GNI	D		±50	mA
θ_{JA}	Package thermal impedance ⁽⁴⁾			113	°C/W
T _{stg}	Storage temperature range		-65	150	°C

⁽¹⁾ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- (2) The input negative-voltage and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
- 3) The value is limited to 5.5 V maximum.
- (4) The package thermal impedance is calculated in accordance with JESD 51-7.

Recommended Operating Conditions(1)

			MIN	MAX	UNIT
V _{CC}	Supply voltage		2	5.5	V
		V _{CC} = 2 V	1.5		
\/	High lovel input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	V _{CC} × 0.7		V
V_{IH}	High-level input voltage	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$	V _{CC} × 0.7		V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	V _{CC} × 0.7		
		$V_{CC} = 2 V$		0.5	
\/	Low-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	V	′ _{CC} × 0.3	V
V_{IL}	Low-level input voltage	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$	V	′ _{CC} × 0.3	V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	V	$'_{\rm CC} \times 0.3$	
V _I	Input voltage		0	5.5	V
Vo	Output voltage		0	V_{CC}	V
		$V_{CC} = 2 V$		-50	μΑ
	High lovel output ourrent	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		-2	
I _{OH}	High-level output current	$V_{CC} = 3 \text{ V to } 3.6 \text{ V}$		-6	mA
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		-12	
		V _{CC} = 2 V		50	μΑ
	Low level output ourrent	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$		2	
I _{OL}	Low-level output current	V _{CC} = 3 V to 3.6 V		6	mA
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$		12	
Б	Futured timing positions	V _{CC} = 2 V	5		kΩ
R _{ext}	External timing resistance	V _{CC} ≥ 3 V	1	KL2	
C _{ext}	External timing capacitance		No restriction		pF
$\Delta t/\Delta V_{CC}$	Power-up ramp rate		1		ms/V
T _A	Operating free-air temperature		-40	105	°C

⁽¹⁾ All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

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THERMAL INFORMATION

		SN74LV123ATPWRQ1	
	THERMAL METRIC ⁽¹⁾	TSSOP – PW	UNITS
		16 PINS	
θ_{JA}	Junction-to-ambient thermal resistance (2)	111.2	
θ_{JCtop}	Junction-to-case (top) thermal resistance (3)	46.1	
θ_{JB}	Junction-to-board thermal resistance (4)	56.3	2004
Ψлт	Junction-to-top characterization parameter ⁽⁵⁾	5.6	°C/W
ΨЈВ	Junction-to-board characterization parameter ⁽⁶⁾	55.7	
θ_{JCbot}	Junction-to-case (bottom) thermal resistance (7)	n/a	

- (1) For more information about traditional and new thermal metrics, see the IC Package Thermal Metrics application report, SPRA953.
- (2) The junction-to-ambient thermal resistance under natural convection is obtained in a simulation on a JEDEC-standard, high-K board, as specified in JESD51-7, in an environment described in JESD51-2a.
- (3) The junction-to-case (top) thermal resistance is obtained by simulating a cold plate test on the package top. No specific JEDEC-standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.
- (4) The junction-to-board thermal resistance is obtained by simulating in an environment with a ring cold plate fixture to control the PCB temperature, as described in JESD51-8.
- (5) The junction-to-top characterization parameter, ψ_{JT} , estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ_{JA} , using a procedure described in JESD51-2a (sections 6 and 7).
- (6) The junction-to-board characterization parameter, ψ_{JB}, estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ_{JA}, using a procedure described in JESD51-2a (sections 6 and 7).
- (7) The junction-to-case (bottom) thermal resistance is obtained by simulating a cold plate test on the exposed (power) pad. No specific JEDEC standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.

Electrical Characteristics

over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	V _{cc}	MIN TYP MAX	UNIT
		I _{OH} = -50 μA	2 V to 5.5 V	V _{CC} - 0.1	
.,		$I_{OH} = -2 \text{ mA}$	2.3 V	2	
V_{OH}		$I_{OH} = -6 \text{ mA}$	3 V	2.48	V
		I _{OH} = -12 mA	4.5 V	3.8	
		I _{OL} = 50 μA	2 V to 5.5 V	0.1	
.,		I _{OL} = 2 mA	2.3 V	0.4	1
V_{OL}		I _{OL} = 6 mA	3 V	0.44	V
		I _{OL} = 12 mA	4.5 V	0.55	5
	R _{ext} /C _{ext} (1)	V _I = 5.5 V or GND	5.5 V	±2.5	5
II		V F F V c CND	0 V	±1	μA
	A, B, and CLR	$V_I = 5.5 \text{ V or GND}$	0 to 5.5 V	±1	
I _{CC}	Quiescent	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V	20	μΑ
			3 V	280)
I_{CC}	Active state (per circuit)	$V_I = V_{CC}$ or GND, $R_{ext}/C_{ext} = 0.5 V_{CC}$	4.5 V	650	μΑ
	(per circuit)		5.5 V	975	5
I _{off}		V_I or $V_O = 0$ to 5.5 V	0 V	Ę	μΑ
		V V 0ND	3.3 V 1.9		_
Ci		$V_I = V_{CC}$ or GND	5 V	1.9	pF

(1) This test is performed with the terminal in the off-state condition.



Timing Requirements

over recommended operating free-air temperature range, V_{CC} = 3.3 V ± 0.3 V (unless otherwise noted) (see Figure 3)

	DADAMET	TED	TEST CO	NDITIONS	T,	λ = 25°C	MIN	MAX	UNIT
PARAMETER		TEST CONDITIONS		MIN	TYP MAX	IVIIIA	IVIAA	UNIT	
	Dulas duration	CLR			5		5		20
ı _w	Pulse duration	A or B trigger			5		5		ns
	Dulas ratriagas tima		D 110	C _{ext} = 100 pF	(1)	76	(1)		ns
ι _{rr}	Pulse retrigger time		$R_{ext} = 1 k\Omega$	C _{ext} = 0.01 μF	(1)	1.8	(1)		μs

⁽¹⁾ See retriggering data in the application information section

Timing Requirements

over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 3)

PARAMETER		ED	TEST CO	TEST CONDITIONS		T _A = 25°C			MAX	UNIT
		TEST CONDITIONS		MIN	TYP	MAX	MIN	WAX	UNIT	
	Dulas duration	CLR			5			5		20
ı _w	Pulse duration	A or B trigger			5			5		ns
	Dulas natrianan tiasa		D 41.0	C _{ext} = 100 pF	(1)	59		(1)		ns
τ _{rr}	Pulse retrigger time		$R_{\text{ext}} = 1 \text{ k}\Omega$	C _{ext} = 0.01 μF	(1)	1.5		(1)		μs

⁽¹⁾ See retriggering data in the application information section

Switching Characteristics

over recommended operating free-air temperature range, V_{CC} = 3.3 V ± 0.3 V (unless otherwise noted) (see Figure 3)

DADAMETED	FROM	то	TEST	T,	4 = 25°C	;	MIN	MAY	UNIT
PARAMETER	(INPUT)	(OUTPUT)	CONDITIONS	DITIONS MIN TYP MAX	IVIIN	MAX	UNIT		
	Ā or B	Q or Q	C _L = 50 pF		11.8	24.1	1	27.5	
t _{pd}	CLR	Q or \overline{Q}			10.5	19.3	1	22	ns
	CLR trigger Q or Q Q	Q or \overline{Q}			12.3	25.9	1	29.5	
			$C_L = 50 \text{ pF}$ $C_{\text{ext}} = 28 \text{ pF}$ $R_{\text{ext}} = 2 \text{ k}\Omega$		182	240		300	ns
t _w ⁽¹⁾		Q or \overline{Q}	$C_L = 50 \text{ pF}$ $C_{ext} = 0.01 \mu\text{F}$ $R_{ext} = 10 k\Omega$	90	100	110	90	110	μs
			$C_L = 50 \text{ pF}$ $C_{\text{ext}} = 0.1 \mu\text{F}$ $R_{\text{ext}} = 10 k\Omega$	0.9	1	1.1	0.9	1.1	ms
$\Delta t_w^{(2)}$			C _L = 50 pF		±1				%

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Switching Characteristics

over recommended operating free-air temperature range, V_{CC} = 5 V ± 0.5 V (unless otherwise noted) (see Figure 3)

PARAMETER	FROM	TO TEST		T,	₄ = 25°C		MIN	MAX	UNIT
	(INPUT)	(OUTPUT)	CONDITIONS	MIN	TYP	MAX	IVIIIN	IVIAA	UNIT
\overline{A} or B Q or \overline{Q}		8.3	14	1	16				
t _{pd}	CLR	Q or $\overline{\mathbb{Q}}$	$C_{L} = 50 \text{ pF}$		7.4	11.4	1	13	ns
1.	CLR trigger	Q or $\overline{\mathbb{Q}}$			8.7	14.9	1	17	

 $[\]begin{array}{ll} \text{(1)} & t_w = \text{Duration of pulse at Q and } \overline{\text{Q}} \text{ outputs} \\ \text{(2)} & \Delta t_w = \text{Output pulse-duration variation (Q and } \overline{\text{Q}}) \text{ between circuits in same package} \\ \end{array}$



Switching Characteristics (continued)

over recommended operating free-air temperature range, V_{CC} = 5 V ± 0.5 V (unless otherwise noted) (see Figure 3)

DADAMETED	FROM	FROM TO (OUTPUT)	TEST	T,	T _A = 25°C			MAX	UNIT
PARAMETER	(INPUT)		CONDITIONS	MIN	TYP	MAX	MIN	IVIAA	UNIT
	t_{w} ⁽¹⁾ Q or $\overline{\mathbb{Q}}$	$C_L = 50 \text{ pF}$ $C_{\text{ext}} = 28 \text{ pF}$ $R_{\text{ext}} = 2 \text{ k}\Omega$		167	200		240	ns	
t _w ⁽¹⁾		C_L = 50 pF C_{ext} = 0.01 µF R_{ext} = 10 k Ω	90	100	110	90	110	μs	
			$C_L = 50 \text{ pF}$ $C_{\text{ext}} = 0.1 \mu\text{F}$ $R_{\text{ext}} = 10 k\Omega$	0.9	1	1.1	0.9	1.1	ms
$\Delta t_w^{(2)}$			C _L = 50 pF		±1				%

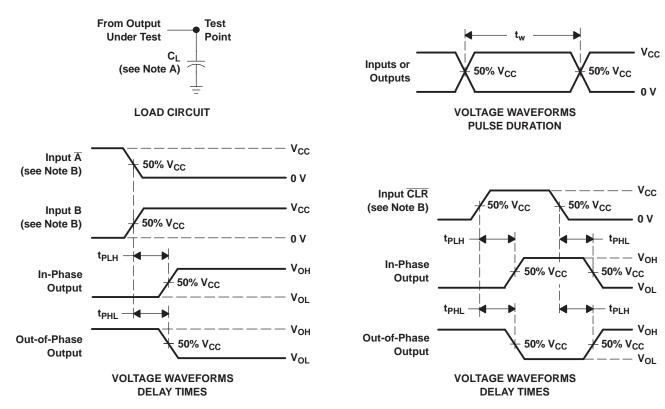
⁽¹⁾ $t_w = Duration of pulse at Q and <math>\overline{Q}$ outputs

Operating Characteristics

 $T_A = 25^{\circ}C$

	PARAMETER	TEST C	V _{CC}	TYP	UNIT	
C _{pd}	Davies discination associations	C _L = 50 pF,	4 40 MH-	3.3 V	44	pF
	Power dissipation capacitance		f = 10 MHz	5 V	49	

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \ \Omega$, $t_f = 3 \ ns$, $t_f = 3 \ ns$.
- C. The outputs are measured one at a time, with one input transition per measurement.

Figure 3. Load Circuit and Voltage Waveforms

⁽²⁾ $\Delta t_w = \text{Output pulse-duration variation (Q and } \overline{Q})$ between circuits in same package



APPLICATION INFORMATION

Operation of the device at these or any other conditions beyond those indicated under *recommended operating* conditions is not implied.

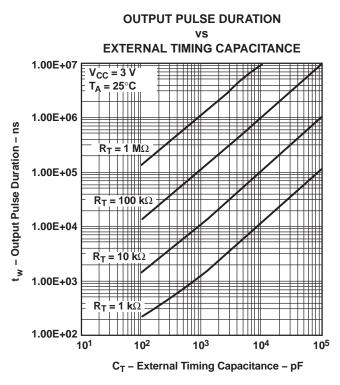


Figure 4.

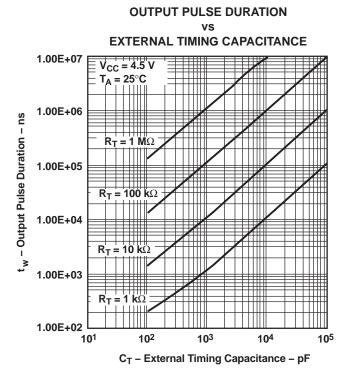
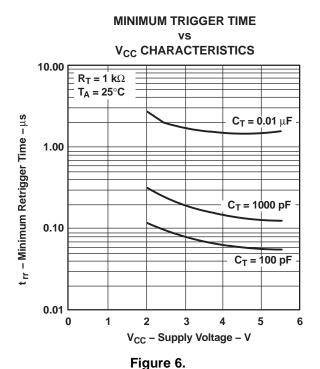


Figure 5.



APPLICATION INFORMATION

Operation of the device at these or any other conditions beyond those indicated under *recommended operating* conditions is not implied.



OUTPUT PULSE-DURATION CONSTANT

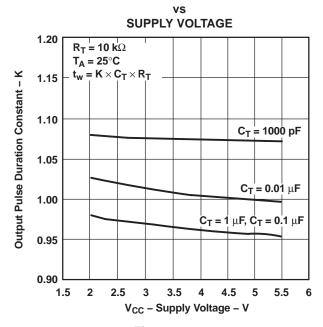


Figure 7.



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Caution In Use

To prevent malfunctions due to noise, connect a high-frequency capacitor between V_{CC} and GND, and keep the wiring between the external components and C_{ext} and R_{ext} / C_{ext} terminals as short as possible.

Power-Down Considerations

Large values of C_{ext} can cause problems when powering down the 'LV123A devices because of the amount of energy stored in the capacitor. When a system containing this device is powered down, the capacitor can discharge from V_{CC} through the protection diodes at pin 2 or pin 14. Current through the input protection diodes must be limited to 30 mA; therefore, the turn-off time of the V_{CC} power supply must not be faster than $t = V_{CC} \times$ C_{ext} / 30 mA. For example, if V_{CC} = 5 V and Cext = 15 pF, the V_{CC} supply must turn off no faster than t = (5 V) × (15 pF) / 30 mA = 2.5 ns. Usually, this is not a problem because power supplies are heavily filtered and cannot discharge at this rate. When a more rapid decrease of V_{CC} to zero occurs, the 'LV123A devices can sustain damage. To avoid this possibility, use external clamping diodes.

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REVISION HISTORY

Cł	hanges from Revision D (April 2008) to Revision E	Pag	e
•	Added thermal information table		4
•	Added Caution section describing power-down timing.		ć







16-Oct-2013

PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
SN74LV123ATPWRG4Q1	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	LV123AQ	Samples
SN74LV123ATPWRQ1	ACTIVE	TSSOP	PW	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-3-260C-168 HR	-40 to 125	LV123AQ	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

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PACKAGE OPTION ADDENDUM

16-Oct-2013

OTHER QUALIFIED VERSIONS OF SN74LV123A-Q1:

● Enhanced Product: SN74LV123A-EP

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Enhanced Product Supports Defense, Aerospace and Medical Applications

PACKAGE MATERIALS INFORMATION

www.ti.com 14-Mar-2013

TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
SN74LV123ATPWRG4Q1	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
SN74LV123ATPWRQ1	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1

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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
SN74LV123ATPWRG4Q1	TSSOP	PW	16	2000	367.0	367.0	35.0	
SN74LV123ATPWRQ1	TSSOP	PW	16	2000	367.0	367.0	35.0	

PW (R-PDSO-G16)

PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M—1994.
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
- E. Falls within JEDEC MO-153



PW (R-PDSO-G16)

PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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